

# 33<sup>rd</sup> workshop AKB – Agenda

November 4<sup>th</sup>/5<sup>th</sup>, 2021



## Agenda, November 4th

From	To	Time	No	Topic	Speaker	Company	Title
14:00	14:40	00:30		Opening	T. Rosenbaum	Infineon	Welcome + member matters
14:40	14:50	00:10	1	P & D	G. Uren	XFAB	Introduction XFAB Paris
14:50	15:30	00:40	2	P & D	M. Mueller	TUD	Overview of Free Software Packages for Compact Modeling
15:30	16:10	00:40	3	P & D	D. Céli	STM	Model Parameter Extraction with QucsStudio
16:10	16:30	00:20		Break / Panel discussion			
16:30	17:10	00:40	4	P & D	K.-W. Pieper	Infineon	Finding root causes of convergence failures in circuit simulation
17:10	17:50	00:40	5	P & D	T. Rosenbaum	Infineon	A look on Characterization of Semiconductor Devices
17:50	18:00	00:10		Closing			
Letter session			11		Z. Huszka	AMS	Revisiting the Extraction of gamma_C

## Agenda, November 5th

From	To	Time	No	Topic	Speaker	Company	Title
08:30	08:40	00:10		Opening	T. Rosenbaum	Infineon	
08:40	09:20	00:40	6	P & D	G. Fischer	IHP	What is the maximum tolerable current density for a SiGe HBT?
09:20	10:00	00:40	7	P & D	C. Weimer	TUD	An experimental approach to investigating device-level RF reliability
10:00	10:40	00:40	8	P & D	F. Sischka	SisConsult	Experiences with using Gummel-Poon Models of Discrete Devices
10:40	11:00	00:20		Break / Panel discussion			
11:00	11:40	00:40	9	P & D	M. Cotorogea	Infineon	Behavioral compact models of IGBTs and Si-diodes for data sheet simulations using a machine learning based calibration strategy
11:40	12:20	00:40	10	P & D	X. Jin	TUD	The characterization and modeling of thermal impedance for advanced HBT with T dependence
12:20	12:30	00:10		Final remarks			



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